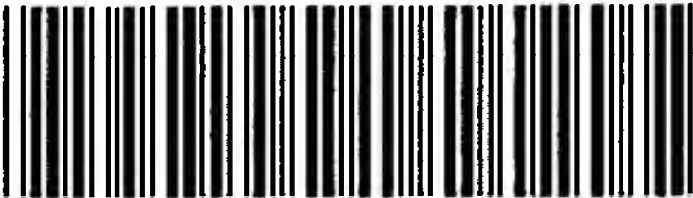


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/806,045	KOURI ET AL.	
	Examiner	Art Unit	
	Phuong Huynh	2857	

SEARCHED			
Class	Subclass	Date	Examiner
702	76	8/5/2005	PH
Updated	Above	5/1/2006	PH
Updated	Above	8/23/2006	PH
356	446, 625	8/23/2006	PH
702	1	8/23/2006	PH
702	66	8/23/2006	PH
702	67	8/23/2006	PH
702	127,134	8/23/2006	PH
Updated	Above	12/15/2006	PH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
702	76	5/1/2006	PH
Updated	Above	8/23/2006	PH
Updated	Above	12/15/2006	PH

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
356/32,34,300,303,450,451,432,445,448,213,228,947,253,254,255,226,340,239,237,222 with text Lippmann-Schwinger	8/5/2005	PH
Consulted with Michael Nghiem for search area as well as double patterning checking	8/2/2005	PH
Consulted with Marc Hoff for searching area: Optics	8/4/2005	PH
Talked with Sang Nguyen for optics search strategy	8/4/2005	PH
Google and IEEE searching (text: Lippmann-Schwinger equation solution; Inverse scattering solotion; approximation method;	8/1/2005	PH
Google and IEEE searching (text: iterative solution, inverse scattering problems	8/1/2005	PH
Consulted with PPrimary Examiner Richard Rosenberger: Cross and search 356/446 and 625	4/27/2006	PH
Inventor search Edan and East with text (See East for details and dates)		PH

Search Notes (continued)



Application/Control No.		Applicant(s)/Patent under Reexamination	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
702/1, 66,67,76, 127, 134; 356/446,625 with text	8/23/2006	PH
Assignment Data (eDan)	8/23/2006	PH
Consulted with SPE. Marc S. Hoff	9/1/2006	PH
702/1, 66,67,76, 127, 134; 356/446,625 with text	12/15/2006	PH